Hybrid 8j150 Traveler

January 18, 2000

1 Connectivity

Repairs on shorts:

Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J150 has die: 200-029 200-030 200-034 200-038 215-019 215-020 215-021 215-022

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j150 classification info. Created 15:57:15 01/14/00

Hybrid 8j150 quality: fair
Chip classification: good fair good fair good good fair good
Bad channels (chip-channel): 6-28
Bad cells: none
Random bad capacitors (chip-cell-channel): 1-38-94 3-17-27 3-29-113
   6-0-28 6-1-28 6-10-28 6-15-28 6-16-28 6-18-28 6-2-28 6-21-28
   6-25-28 6-27-28 6-28-28 6-3-28 6-30-28 6-32-28 6-34-28 6-35-28
   6-39-28 6-4-28 6-40-28 6-42-28 6-43-28 6-5-28 6-8-28
Channels at pedestal needed for DCMS: 30.6 32.2 31.6 31.6 32.6 30.6 30.7 31.6
```

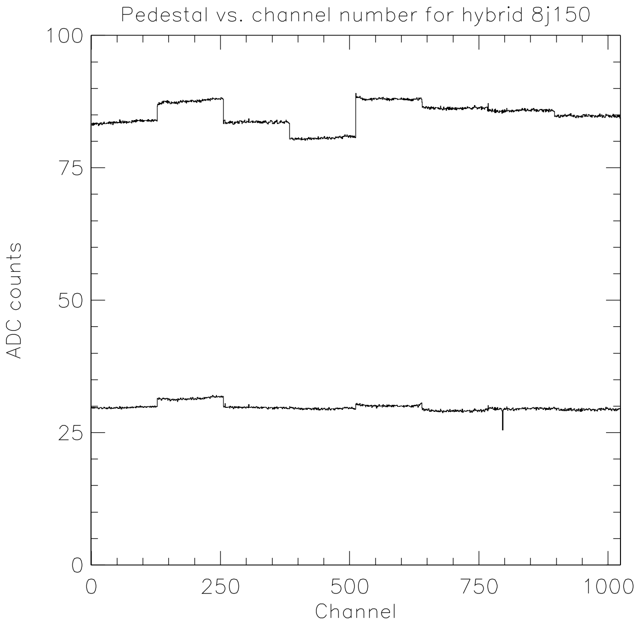
4 Comments

No comments.

5 Pedestal

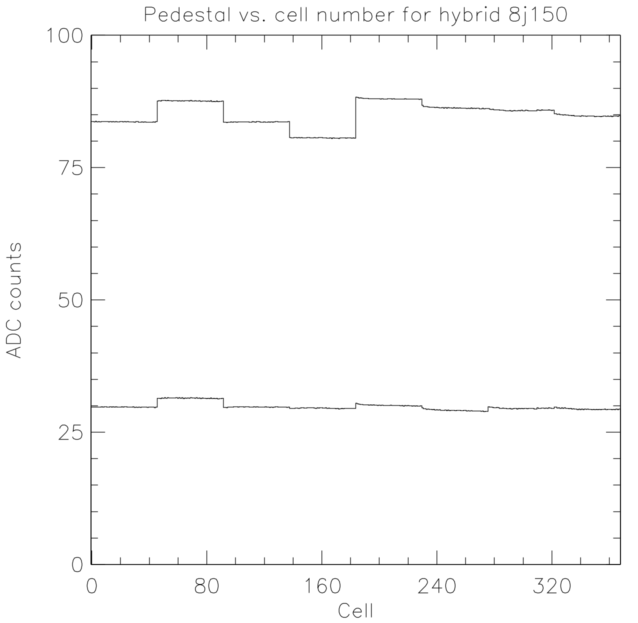
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

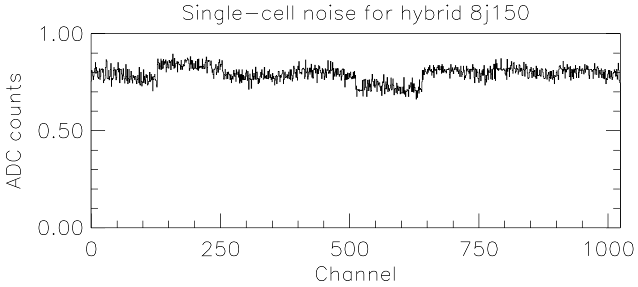
Pedestal vs. Pipeline Cell ID

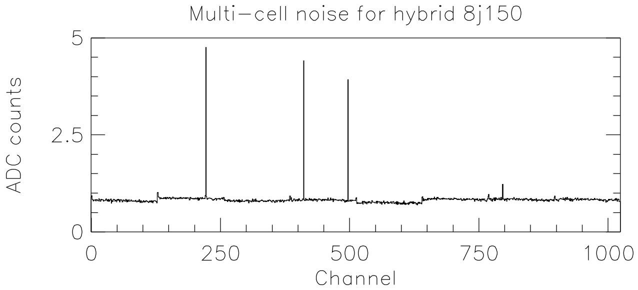


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

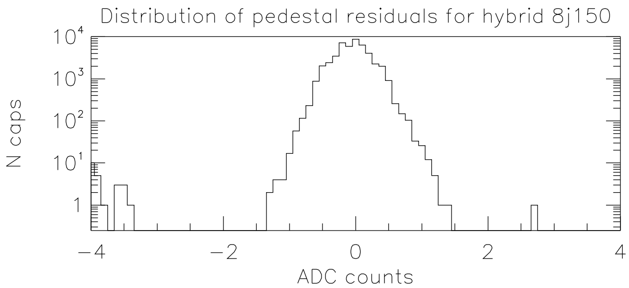
RMS Noise

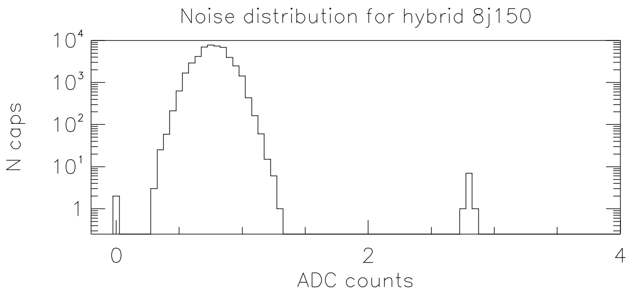




The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in